

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**In re application of:** Cheng et al.

**Patent No.** 7,200,786

**Issued:** April 3, 2007

**Application No.** 10/749,283

**Filed:** December 30, 2003

**Confirmation No.** 9850

**For:** BUILT-IN SELF-ANALYZER FOR  
EMBEDDED MEMORY

**Examiner:** Phung M. Chung

**Art Unit:** 2138

**Attorney Reference No.** 1011-66273-01

**FILED VIA EFS  
ON FEBRUARY 25, 2010**

FILED VIA EFS  
COMMISSIONER FOR PATENTS

REQUEST FOR CERTIFICATE OF CORRECTION

The following printing errors were noted in comparing the printed patent with the papers in the attorneys' files:

In the Claims:

Column 23, line 32, "The circuit of claim 39" should read --The circuit of claim 43--.

All of the above errors are attributable to the Patent Office, and a Certificate of Correction is enclosed to make formal notice of the errors in the referenced patent.

Respectfully submitted,

One World Trade Center, Suite 1600  
121 S.W. Salmon Street  
Portland, Oregon 97204  
Telephone: (503) 595-5300  
Facsimile: (503) 595-5301  
cc: Client  
Docketing

KLARQUIST SPARKMAN, LLP

By                     /Patrick M. Bible/                      
Patrick M. Bible  
Registration No. 44,423

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 7,200,786  
APPLICATION NO. : 10/749,283  
ISSUE DATE : April 3, 2007  
INVENTOR(S) : Cheng et al.

Page 1 of 1

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the Claims:

Column 23, line 32, "The circuit of claim 39" should read --The circuit of claim 43--.

MAILING ADDRESS OF SENDER:

Klarquist Sparkman, LLP  
One World Trade Center, Suite 1600  
121 SW Salmon Street  
Portland Oregon, 97204